NOTICE OF H	NOTICE OF REVISION (NOR)					
This revision described below has been						
Public reporting burden for this collection reviewing instructions, searching existing completing and reviewing the collection of informat: other aspect of this collection of informat	is estimated to average 2 hour data sources, gathering and main information. Send comments reg ion, including suggestions for :	s per response, incl ntaining the data ne arding this burden e reducing this burder	Luding the time for eeded, and estimate or any A, to Department of	2. PROCURING ACTIVITY NO.		
Defense, Washingtion Headquarters Services, Davis Highway, Suite 1204, Arlington, VA 22. Reduction Project (0704-0188), Washington, J ADDRESSED, RETURN COMPLETED FORM TO THE GO ACTIVITY NUMBER LISTED IN ITEM 2 OF THIS FOI	Directorate for Information Op 202-4302, and to the Office of 1 DC 20503. PLEASE DO NOT RETURN VERNMENT ISSUING CONTRACTING OF RM.	Anagement and Reports Management and Budge YOUR COMPLETED FORM FICER FOR THE CONTRA	5, 1215 Jefferson et, Paperwork 4 TO EITHER OF THESE ACT/ PROCURING	3. DODAAC		
4. ORIGINATOR	b. ADDRESS (Street, City, St Code)	ate, Zip	5. CAGE CODE 67268	6. NOR NO. 5962-R003-94		
a. TYPED NAME (First, Middle Initial, Last)	Defense Electronics S 1507 Wilmington Pike Dayton, OH 45444-527()	7. CAGE CODE 67268	8. DOCUMENT NO. 5962-89642		
9. TITLE OF DOCUMENT	•	10. REVISION I	ETTER	11. ECP NO.		
MICROCIRCUIT, LINEAR, WIDEBAND, HI	GH OUTPUT CURRENT, FAST	a. CURRENT	b. NEW	No users		
SETTLING, OPERATIONAL AMPLIFIER, M	IONOLITHIC SILICON	A	В	listed		
12. CONFIGURATION ITEM (OR SYSTEM) TO WHI All	CH ECP APPLIES					
13. DESCRIPTION OF REVISION						
<pre>13. DESCRIPTION OF REVISION Sheet 1: Revisions ltr column; add "B". Revisions date column; add "40"-03". Revisions date column; add "9". Revision level block; add "B". Rev status of sheets; For sheets 1 and 4, add "B". Sheet 4: TABLE I. Output current test. For +I_{OUT}, under the conditions column, delete "V_{OUT} = -10 V" and substitute "V_{OUT} = 0 V". For -I_{OUT}, under the conditions column, delete "V_{OUT} = +10 V" and substitute "V_{OUT} = 0 V". Revision level block; add "B". Revision level block; add "B". </pre>						
14. THIS SECTION FOR GOVERNMENT USE	C ONLY					
a. (X one) X (1) Existing	document supplemented by	the NOR may be	used in manufactu	rate this change		
(2) Revised ((3) Custodian	n of master document shal	l make above rev	vision and furnish	n revised		
document.						
DESC		MICHAEL A.	FRYE	, 1450,		
d. TITLE	e. SIGNATURE		f. DATE SIGNED			
CHIEF, MICROFLECTRONICS BRANCH	MICHAEL A. FRVE		(YYMMDD) 94-01-03			
15a. ACTIVITY ACCOMPLISHING REVISION	b. REVISION COMPLETED (Signa	uture)	c. DATE SIGNED			
	((YYMMDD)			
	RICK C. OFFICER	ions are chaole	+=			

NOTICE OF REVISION (NOR) (See MIL-STD-480 for instructions) This revision described below has been authorized for the document liste Public reporting burden for this collection is estimated to average 1 ho instructions, searching existing data sources, gathering and maintaining the collection of information. Send comments regarding this burden esti information, including suggestions for reducing this burden, to Washingt Information Operations and Reports, 1215 Jefferson Davis Highway, Suite of Information and Regulatory Affairs, Office of Management and Budget, 1. ORIGINATOR NAME AND ADDRESS Defense Electronics Supply Center Dayton, Ohio 45444-5277	DATE (YYMMDD) 93-04-06 wur per response, including the the data needed, and completing mate or any other aspect of th con Headquarters Services, Direc 1204, Arlington, VA 22202-4302 Washington, DC 20503. 2. CAGE CODE 67268	Form Approved OMB No. 0704-0188 time for reviewing ng and reviewing is collection of ctorate for , and to the Office					
 Public reporting burden for this collection is estimated to average 1 he instructions, searching existing data sources, gathering and maintaining the collection of information. Send comments regarding this burden esti information, including suggestions for reducing this burden, to Washingt Information Operations and Reports, 1215 Jefferson Davis Highway, Suite of Information and Regulatory Affairs, Office of Management and Budget, 1. ORIGINATOR NAME AND ADDRESS Defense Electronics Supply Center Dayton, Ohio 45444-5277 	bur per response, including the the data needed, and completi: mate or any other aspect of th ion Headquarters Services, Dire 1204, Arlington, VA 22202-4302 Washington, DC 20503. 2. CAGE CODE 67268	time for reviewing ng and reviewing is collection of ctorate for , and to the Office					
 ORIGINATOR NAME AND ADDRESS Defense Electronics Supply Center Dayton, Ohio 45444-5277 	2. CAGE CODE						
Defense Electronics Supply Center Dayton, Ohio 45444-5277	67269	3. NOR NO.					
	0/200	5962-R074-93					
	4. CAGE CODE	5. DOCUMENT					
	67268	NO.					
	07200	5502-85042					
6. TITLE OF DOCUMENT	7. REVISION						
	LETTER (Current) New	(New) A					
Mckts, Linear, Wideband, High Output Current, Fast settlin	ng,	(
Operational Amplifier, Monolithic Silicon	No registered	users					
9. CONFIGURATION ITEM (OR SYSTEM) TO WHICH ECP APPLIES All							
10 DESCRIPTION OF REVISION							
Sheet 1. Perisions ltr column, add Wall							
Revisions description column; add "Changes in accordance w Revisions date column; add "93-04-06". Revision level block; add "A". Rev status above sheet number 1, 4, 5, and 6, add "A".	Sheet 1: Revisions ltr column; add "A". Revisions description column; add "Changes in accordance with NOR 5962-R074-93". Revisions date column; add "93-04-06". Revision level block; add "A". Bey status above sheet number 1 4 5 and 6 add "A".						
Sheet 4: Table I, Input bias current test, -I _B , subgroup 1, delete and 3, delete "-12" min and substitute "+12" max. Revision level block; add "A".	"-8" min and substitute "+8"	max, subgroups 2					
Sheet 5: Table I, Common mode rejection ratio test, +CMRR and -CMRR substitute subgroup "1" (two places), delete subgroups "5 "2 and 3" (two places). Revision level block; add "A".	, delete subgroup "4" (two pl and 6" (two places) and subst	aces) and itute subgroups					
Sheet 6: Table I, Slew rate, +SR and -SR, delete subgroup "4" (two places), delete subgroups "5 and 6" (two places) and subst Revision level block; add "A".	places) and substitute subgro itute subgroups "10 and 11" (up "9" (two two places).					
11. THIS SECTION FOR GOVERNMENT USE ONLY							
a. CHECK ONE [X]EXISTING DOCUMENT SUPPLEMENTED BY THIS NOR MAY BE USED IN MANUFACTURE. [] REVISED DOCUMENT MUST BE RECEIVED BEFORE MANUFACTU MAY INCORPORATE THIS CHAN	[] CUSTODIAN OF MAST JRER SHALL MAKE ABOVE IGE. FURNISH REVISED D	ER DOCUMENT REVISION AND OCUMENT TO:					
b. ACTIVITY AUTHORIZED TO SIGNATURE AND TITLE	DATE (YYMMDD)						
APPROVE CHANGE FOR GOVERNMENT Michael A Frye	93-04-06						
IZ. ACTIVITI ACCOMPLISHING REVISION COMPLETED (Signature) DATE (YYMMDD)						
REVISION							

								R	EVISI	ONS			-							
LTR					D	ESCF		DN					DA	TE (YF	R-MO-D	A)		APPR)
															<u> </u>	<u>A)</u>				<u>,</u>
REV																				
SHEET																				
REV																				
SHEET																				
REV STATU	IS			RE\	/															
OF SHEETS	5			SHE	ET		1	2	3	4	5	6	7	8	9	10				
PMIC N/A				PREP Rick (PARED Officer	BY				DE	FENS	SE EI	LECT DAY	roi Ton	NICS , OHI	SUF	PLY 5444		NTER	R
STAND		DIZE RY	:D	CHEC Charli	CKED E	BY pre					יחסי		•і IIT						шсь	
DRAWING APPROVED BY THIS DRAWING IS AVAILABLE Michael A. Frye OPERATIONAL AMPLIFIER, MONOL			ING, DLITI	HIC	1															
DEPAR AND AGEN DEPARTMEN	RTMEN ICIES (IT OF I	NTS OF TH DEFEN	E ISE	DRAV	VING / 92-07	APPRO 7-16	VAL DA	TE		SIZE		CAG	E COD	E		59	62-	896	42	
AMSC 1	N/A			REVIS	SION L	EVEL				Α		6	5726	8						
										SHE	ET	1	OF	1()					

1.1 <u>Scope</u> . This drawing describes device requirements for "Provisions for the use of MIL-STD-883 in conjunction with comp	or class B microcirc pliant non-JAN devi	uits in accordance with 1.2 ces".	2.1 of MIL-STD-883,			
1.2 Part or Identifying Number (PIN). The complete PIN shall	l be as shown in the	following example:				
<u>5962-89642</u> <u>01</u> <u>C</u>	<u>X</u>					
	and finish par					
(1.2.1) (1.2.2) N	11L-M-38510					
1.2.1 <u>Device type(s)</u> . The device type(s) shall identify the circl	uit function as follow	vs:				
Device type Generic number	Circuit functio	<u>on</u>				
01 AD842 Widel	band, high output c	urrent, fast settling, operatio	nal amplifier			
1.2.2 <u>Case outline(s)</u> . The case outline(s) shall be as designated	ated in NIL-STD-183	35, and as follows:				
Outline letter Descriptive designator	Terminals	Package s	tyle			
C GDIP1-T14 or CDIP2-T14 X See figure 1	14 12	Dual-in-line Can	e			
2 CQCC1-N20	20	Square lea	dless chip carrier			
Notice integrationSecond Second						
levels may degrade performance and affect reliability. <u>2</u> / Unless otherwise specified, $T_{\Delta} = +25^{\circ}$ C.						
<u>3</u> / Derate linearly above $T_A = +25^{\circ}$ C for case C at 8.7 mW/°	C, case X at 10 mV	$V/^{\circ}C$, and case 2 at 6.7 mW	//° C.			
STANDARDIZED MILITARY DRAWING	SIZE A		5962-89642			
DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444		REVISION LEVEL	SHEET 4			

2. APPLICABLE DOCUMENTS

2.1 <u>Government specification, standard, and bulletin</u>. Unless otherwise specified, the following specification, standard, and bulletin of the issue listed in that issue of the Department of Defense Index of Specifications and Standards specified in the solicitation, form a part of this drawing to the extent specified herein.

SPECIFICATION

MILITARY

MIL-M-38510 - Microcircuits, General Specification for.

STANDARD

MILITARY

MIL-STD-883- Test Methods and Procedures for Microelectronics.MIL-STD-1835- Microcircuit Case Outlines.

BULLETIN

MILITARY

MIL-BUL-103 - List of Standardized Military Drawings (SMD's).

(Copies of the specification, standard, and bulletin required by manufacturers in connection with specific acquisition functions should be obtained from the contracting activity or as directed by the contracting activity.)

2.2 <u>Order of precedence</u>. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing shall take precedence.

3. REQUIREMENTS

3.1 <u>Item requirements</u>. The individual item requirements shall be in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices" and as specified herein.

3.2 <u>Design, construction, and physical dimensions</u>. The design, construction, and physical dimensions shall be as specified in MIL-M-38510 and herein.

3.2.1 <u>Case outline(s)</u>. The case outline(s) shall be in accordance with 1.2.2 herein and figure 1.

3.2.2 <u>Terminal connections</u>. The terminal connections shall be as specified on figure 2.

3.3 <u>Electrical performance characteristics</u>. Unless otherwise specified herein, the electrical performance characteristics are as specified in table I and shall apply over the full ambient operating temperature range.

3.4 <u>Electrical test requirements</u>. The electrical test requirements shall be the subgroups specified in table II. The electrical tests for each subgroup are described in table I.

3.5 <u>Marking</u>. Marking shall be in accordance with MIL-STD-883 (see 3.1 herein). The part shall be marked with the PIN listed in 1.2 herein. In addition, the manufacturer's PIN may also be marked as listed in MIL-BUL-103 (see 6.6 herein).

3.6 <u>Certificate of compliance</u>. A certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in MIL-BUL-103 (see 6.6 herein). The certificate of compliance submitted to DESC-ECS prior to listing as an approved source of supply shall affirm that the manufacturer's product meets the requirements of MIL-STD-883 (see 3.1 herein) and the requirements herein.

STANDARDIZED MILITARY DRAWING	SIZE A		5962-89642
DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444		REVISION LEVEL	SHEET 5

TABLE I. Electrical performance characteristics.							
Test	Symbol	Conditions <u>1</u> , -55° C ≤ T _A ≤ +7 V± = ±15 V	/ 125°C	Group A subgroups	Limits	<u>2</u> /	Unit
		unless otherwise s	specified		Min	Max	
Input offset voltage	V _{IO}	$V_{CM} = 0 V$		1	-1.5	+1.5	mV
				2,3	-3.5	+3.5	
Input bias current	+I _B	$V_{CM} = 0 V$		1		+8	μA
				2,3		+12	<u> </u>
	-I _B	V _{CM} = 0 V	$V_{CM} = 0 V$		-8		<u> </u>
				2,3	-12		
Input offset current	I _{IO}	V _{CM} = 0 V		1	-0.4	+0.4	μA
				2,3	-0.6	+0.6	
Common mode voltage range	+V _{CM}	V+ = 5.0 V, V- = -25 V _{OUT} = -10 V	5 V,	1,2,3	10		V
	-V _{CM}	V+ = 25 V, V- = -5.0 V _{OUT} = 10 V	V+ = 25 V, V- = -5.0 V, V _{OUT} = 10 V			-10	
Large signal voltage gain	+A _{VOL}	$V_{OUT} = 0 V \text{ and } 10 V,$ $R_L = 500\Omega$		1	40		V/mV
				2,3	20		+
	-A _{VOL}	$V_{OUT} = 0 V and -10$) V,	1	40		+
		$R_{L} = 50002$		2,3	20		<u> </u>
Output current	+I _{OUT}	V _{OUT} = -10 V, T _A =	= +25° C	1	100		mA
	-I _{OUT}	V _{OUT} = +10 V, T _A =	= +25° C	1		-100	
Output voltage swing	+V _{OUT}	R _L = 500Ω		1,2,3	10		V
	-V _{OUT}	R _L = 500Ω		1,2,3		-10	
Quiescent power supply	+I _{CC}	V _{OUT} = 0 V, I _{OUT} =	= 0 mA	1		+14	mA
current				2,3		+19	
	-I _{CC}	$V_{OUT} = 0 V, I_{OUT} = 0 mA$			-14		
				2,3	-19		
See footnotes at end of table.							
	SIZE A			5962	-89642		
MILLIARY DRAWING DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444				REVISION LEVE	EL	SHEET	6

	TABLE I.	Electrical performar	nce characteristic	<u>s</u> - Continued.			
Test	Symbol	Conditions <u>1</u> / -55° C ≤ T _A ≤ +1 V± = ±15 V	′ I25°C	Group A subgroups	Limits	<u>2</u> /	Unit
		unless otherwise s	specified		Min	Max	
Power supply rejection ratio	+PSRR	V+ = 5.0 V to 18 V,	V- = -15 V	1	86		dB
				2,3	80		
	-PSRR	V- = -5.0 V to -18 V	, V+ = +15 V		86		
				2,3	80		
Quiescent power	P _C	V _{OUT} = 0 V, I _{OUT} =	/ _{OUT} = 0 V, I _{OUT} = 0 mA			420	mW
consumption <u>3</u> /				2,3		570	
Differential input resistance <u>4</u> /	R _{IN}	V _{CM} = 0 V, T _A = +2	5° C	4	50		kΩ
Gain bandwidth product <u>4</u> /	GBWP	$V_{OUT} = \pm 100 \text{ mV}, \text{ F}_{1} = 100 \text{ kHz}, \text{ f}_{2} = 100 k$	R _L = 500Ω, 0 MHz,	4	50		MHz
Full power bandwidth <u>4/ 5</u> /	FPBW	V _{PK} = 10 V, R _L = 50 T _A = +25°C	00Ω,	4	4.7		MHz
Closed loop stable gain <u>4</u> /	CLSG	$R_L = 500\Omega, C_L \le 10$ $T_A = +25°C$) pF,	4	2		V/V
Common mode rejection ratio	+CMRR	Delta V _{CM} = 10 V, V V- = -25 V, V _{OUT} =	/+ = 5.0 V, -10 V	4	86		dB
				5,6	80		
	-CMRR	Delta V _{CM} = -10 V,	V+ = 25 V,	4	86		
		•- = -3.0 •, •OUT -	- 10 V	5,6	80		
Settling time <u>4</u> /	t _S	$A_V = -2 V/V, 10 V s$ of the final value, $R_L = 500\Omega, T_A = +2$	tep at 0.1% 25°C	9		150	ns
		$A_V = -2 V/V, 10 V s$ of the final value, $R_L = 500\Omega, T_A = +2$	tep to 0.01% 25° C	9		200	
See footnotes at end of table.	-				ł	+	
STANDA MILITARY I	RDIZED DRAWING		SIZE A			5962	2-89642
DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444			REVISION LEVI	EL	SHEET	7	

TABLE I. Electrical performance characteristics.						
Test	Symbol Conditions $1/$ -55° C \leq T _A \leq +125° C s			Limits	Unit	
		V± = ±15 V unless otherwise specified		Min	Max	
Overshoot <u>4</u> /	+OS	$V_{OUT} = 0 V \text{ to } +200 \text{ mV}, A_V +2, R_L = 500\Omega, T_A = +25^{\circ} \text{ C}$	9		50	%
	-OS	$V_{OUT} = 0 V \text{ to } -200 \text{ mV}, A_V = +2, R_L = 500\Omega, T_A = +25^{\circ} \text{ C}$	9		50	
Slew rate <u>4</u> /	w rate 4/ +SR $V_{OUT} = -5.0$ V to 5.0 V, rising edge,		_4	300		V/µs
		$R_L = 500\Omega$, $A_V = -2$ V/V, measured from 10 percent to 90 percent point	5,6	200		
	-SR	V _{OUT} = 5.0 V to -5.0 V, falling edge,	4	300		
		$R_L = 500\Omega$, $A_V = -2$ V/V, measured from 90 percent to 10 percent point	5,6	200		
Rise time <u>4</u> / <u>6</u> /	t _R	$V_{OUT} = 0$ V to +200 mV, A _V = +2, R _L = 500 Ω	9,10,11		10	ns
Fall time <u>4/ 6</u> /	t _F	$V_{OUT} = 0$ V to -200 mV, A _V = +2, R _L = 500 Ω	9,10,11		10	ns

 $\underline{1}/$ Unless otherwise specified, for dc tests, R_L = 100 Ω and V_{OUT} = 0 V.

2/ The algebraic convention, whereby the most negative value is a minimum and the most positive is a maximum, is used in this table. Negative current shall be defined as conventional current flow out of a device terminal.

3/ Quiescent power consumption is based on quiescent supply current test maximum with no load on outputs.

4/ If not tested, shall be guaranteed to the limits specified in table I herein.

 $\underline{5}$ / Full power bandwidth = \underline{SR} 2 π V_{PK}

6/ Rise and fall times measured between 10 percent to 90 percent point.

3.7 <u>Certificate of conformance</u>. A certificate of conformance as required in MIL-STD-883 (see 3.1 herein) shall be provided with each lot of microcircuits delivered to this drawing.

3.8 Notification of change. Notification of change to DESC-ECS shall be required in accordance with MIL-STD-883 (see 3.1 herein).

3.9 <u>Verification and review</u>. DESC, DESC's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.

	_		
STANDARDIZED MILITARY DRAWING	SIZE A		5962-89642
DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444		REVISION LEVEL	SHEET 8





Symbol	Inche	es	Millimeters		Notes	
	Min	Max	Min	Max		
А	0.148	0.181	3.76	4.60		
фb	0.016	0.019	0.41	0.48	1	
φb ₁	0.016	0.021	0.41	0.53	1	
φD	0.592	0.615	15.04	15.62		
φD ₁	0.545	0.555	13.84	14.10		
е	0.400 BSC		10.16 B	SC	3	
e ₁	0.200 E	0.200 BSC		5.00 BSC		
e ₂	0.100 E	BSC	2.54 BS	SC	3	
F		0.040		1.02		
k	0.026	0.036	0.66	0.91		
k ₁	0.027	0.037	0.68	0.94	2	
L	0.375		9.50			
L ₁		0.050		1.27	1	
Q	0.010	0.045	0.25	1.14		

NOTES:

- 1. (All leads) φb applies between L and L1, φb_1 applies between L1 and 0.375 inch (9.50 mm) from the reference plane. Diameter is uncontrolled in L_1 and beyond 0.375 inch (9.50 mm) from the reference plane. 2. Measured from the maximum diameter of the
- product.
- 3. Leads having a maximum diameter 0.019 inch (0.48 mm) measured in gauging plane 0.054 inch (1.37 mm) + 0.001 inch (0.03 mm) - 0.000 inch (0.000 mm) below the base plane of the product are within 0.007 inch (0.18 mm) of their true position relative to the maximum width tab.

FIGURE 1.	<u>Case outline X</u> .		
STANDARDIZED MILITARY DRAWING	SIZE A		5962-89642
DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444		REVISION LEVEL	SHEET 9
FORM 400A		-	

Device type		01	
Case outlines	С	х	2
Terminal number	Termina	l symbol	
1	NC	NC	NC
2	NC	NC	Balance
3	Balance	Balance	NC
4	Input-	Balance	NC
5	Input+	Input-	Input-
6	V-	Input+	NC
7	NC	NC	Input+
8	NC	NC	NC
9	NC	NC	NC
10	Output	V-	V-
11	V+	Output	NC
12	NC	V+	NC
13	Balance		NC
14	NC		NC
15			Output
16			NC
17			V+
18			NC
19			NC
20			Balance

NC = No connection

FIGURE 2. Terminal connections.

STANDARDIZED MILITARY DRAWING DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444	SIZE A		5962-89642
		REVISION LEVEL	SHEET 10

4. QUALITY ASSURANCE PROVISIONS

4.1 <u>Sampling and inspection</u>. Sampling and inspection procedures shall be in accordance with section 4 of MIL-M-38510 to the extent specified in MIL-STD-883 (see 3.1 herein).

4.2 <u>Screening</u>. Screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection. The following additional criteria shall apply:

- a. Burn-in test, method 1015 of MIL-STD-883.
 - (1) Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.6 herein).
 - (2) $T_A = +125^{\circ}C$, minimum.
- b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.

MIL-STD-883 test requirements	Subgroups (per method 5005, table I)
Interim electrical parameters (method 5004)	1,4
Final electrical test parameters (method 5005)	1*,2,3,4
Group A test requirements (method 5004)	1,2,3,4,5,6, 9**,10**,11**
Groups C and D end-point electrical parameters (method 5005)	1

TABLE II. Electrical test requirements.

* PDA applies to subgroup 1.

** Subgroups 9, 10, and 11, if not tested, shall be guaranteed to the limits specified in table I.

4.3 <u>Quality conformance inspection</u>. Quality conformance inspection shall be in accordance with method 5005 of MIL-STD-883 including groups A, B, C, and D inspections. The following additional criteria shall apply.

4.3.1 Group A inspection.

- a. Tests shall be as specified in table II herein.
- b. Subgroups 5, 6, 7, and 8 in table I, method 5005 of MIL-STD-883 shall be omitted.

4.3.2 Groups C and D inspections.

- a. End-point electrical parameters shall be as specified in table II herein.
- b. Steady-state life test conditions, method 1005 of MIL-STD-883.
 - (1) Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.6 herein).
 - (2) $T_A = +125^{\circ}C$, minimum.
- (3) Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.

STANDARDIZED MILITARY DRAWING DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444	SIZE A		5962-89642
		REVISION LEVEL	SHEET 11

5. PACKAGING

5.1 <u>Packaging requirements</u>. The requirements for packaging shall be in accordance with MIL-M-38510.

6. NOTES

6.1 <u>Intended use</u>. Microcircuits conforming to this drawing are intended for use when military specifications do not exist and qualified military devices that will perform the required function are not available for OEM application. When a military specification exists and the product covered by this drawing has been qualified for listing on QPL-38510, the device specified herein will be inactivated and will not be used for new design. The QPL-38510 product shall be the preferred item for all applications.

6.2 <u>Replaceability</u>. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.

6.3 <u>Configuration control of SMD's</u>. All proposed changes to existing SMD's will be coordinated with the users of record for the individual documents. This coordination will be accomplished in accordance with MIL-STD-481 using DD Form 1693, Engineering Change Proposal (Short Form).

6.4 <u>Record of users</u>. Military and industrial users shall inform Defense Electronics Supply Center when a system application requires configuration control and the applicable SMD. DESC will maintain a record of users and this list will be used for coordination and distribution of changes to the drawings. Users of drawings covering microelectronics devices (FSC 5962) should contact DESC-ECS, telephone (513) 296-6021.

6.5 Comments. Comments on this drawing should be directed to DESC-ECS, Dayton, Ohio 45444, or telephone (513) 296-5377.

6.6 <u>Approved sources of supply</u>. Approved sources of supply are listed in MIL-BUL-103. The vendors listed in MIL-BUL-103 have agreed to this drawing and a certificate of compliance (see 3.6 herein) has been submitted to and accepted by DESC-ECS.

STANDARDIZED MILITARY DRAWING DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444	SIZE A		5962-89642
		REVISION LEVEL	SHEET 12

STANDARDIZED MILITARY DRAWING SOURCE APPROVAL BULLETIN

DATE: 92-07-16

Approved sources of supply for SMD 5962-89642 are listed below for immediate acquisition only and shall be added to MIL-BUL-103 during the next revision. MIL-BUL-103 will be revised to include the addition or deletion of sources. The vendors listed below have agreed to this drawing and a certificate of compliance has been submitted to and accepted by DESC-ECS. This bulletin is superseded by the next dated revision of MIL-BUL-103.

Standardized military drawing PIN	Vendor CAGE number	Vendor similar PIN <u>1</u> /
5962-8964201CX	24355	AD842SQ/883B
5962-8964201XX	24355	AD842SH/883B
5962-89642012X	24355	AD842SE/883B

<u>1</u>/ <u>Caution</u>. Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.

Vendor CAGE <u>number</u> Vendor name and address

24355

Analog Devices Route 1 Industrial Park P.O. Box 9106 Norwood, MA 02062 Point of contact: 804 Woburn Street Wilmington, MA 01887-3642

The information contained herein is disseminated for convenience only and the Government assumes no liability whatsoever for any inaccuracies in this information bulletin.